

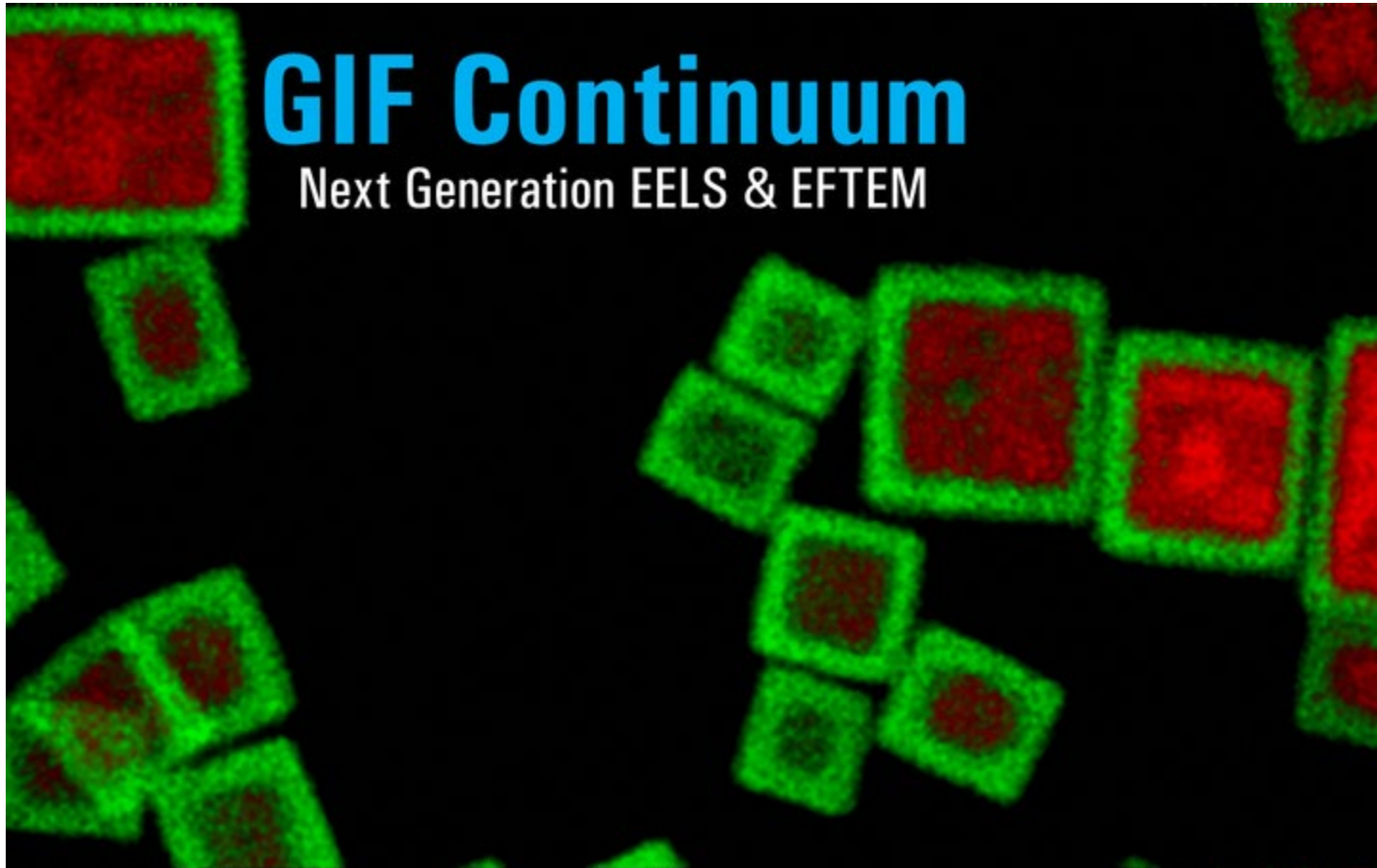
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Electron detectors for counted EELS acquisition

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Abstract



Direct detection (DD) cameras operating in single-electron counting mode dramatically improve detector resolution and noise budget giving accordingly dramatic improvements in EELS data. However, designing a detector optimized for both low- and high-voltages is very challenging. In this talk, we will discuss these challenges and present counted EELS data at several voltages to demonstrate how these challenges can be overcome.

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